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AN-4171

FAN7085 High-Side Gate Driver- Internal Recharge Path Design Considerations

Introduction

The FAN7085_GF085 (heretofore referred to as the FAN7085) is a high-side gate drive IC with reset input¹ and built-in recharge FET (see reference # for a detailed data sheet). It is designed for high voltage and high speed driving of MOSFET's or IGBT's, which operate up to 300 V. The package and pin assignments are shown in Figure 1.

SOIC-8

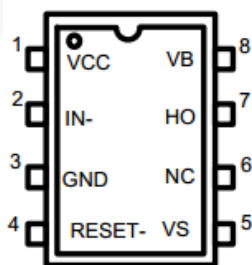


Figure 1. Package and Pin Assignments

Figure 2 is a diagram, from the data sheet, showing all the functional blocks. One key feature of the product and the focus of this application note is the internal recharge path (highlighted in red on the diagram). Applications and design information can be found in Fairchild applications notes (see references #, # and #). These three references are provided for those readers not familiar with the product note, all the details of the product will not be repeated here.

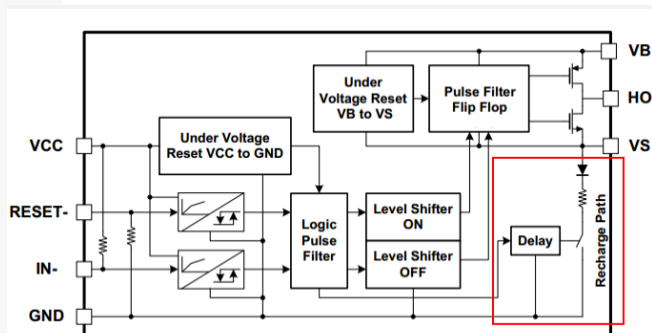


Figure 2. Functional Block Diagram

The purpose of the recharge path is to provide a way to recharge the external boot capacitor when it is not possible with an externally connected application circuit. When the recharge path is active with these particular circuits, the voltage between the V_S pin and the ground pin can be high enough that extra analysis is needed. The purpose of this application note is to describe the analysis needed to avoid over stressing the product.

Although the recharge circuit shown in the functional block diagram is a *switch* in series with a *resistor*, it is physically implemented as a MOSFET. The switch represents a gate controlled MOSFET and the resistor represents the $R_{DS(on)}$ of that MOSFET.

¹ As an aside, it's important to point out that the reset feature could be more accurately named an enable function. That is, internal to the chip, the RESET pin and the IN pin are simply negated inputs to an AND gate and that combination is used internally. The RESET pin, just like the IN pin, cannot directly reset the high-side flip flop, but the RESET pin acts in conjunction with the IN pin (AND-like function) to drive the HO output pin (see references # and #).

Valid Use the Recharge Path

To start, consider the absolute maximum ratings for the FAN7085 as specified in the data sheet², extracted and shown in Table 1. Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur.

Table 1. Absolute Maximum Ratings

Parameter		Symbol	Min.	Max	Unit
High-Side Floating Supply Voltage		V_{BS}	-0.3	25.0	V
High-Side Driver Output Stage Voltage, Negative Transient: 0.5 ms, External MOSFET Off		V_B	-5	325	V
High-Side Floating Supply Offset Voltage, Negative Transient: 0.2 μ s		V_S	-25	300	V
High-Side Floating Output Voltage		V_{HO}	$V_S - 0.3$	$V_B + 0.3$	V
Supply Voltage		V_{CC}	-0.3	25.0	V
Input Voltage for IN-		V_{IN}	-0.3	$V_{CC} + 0.3$	V
Input Voltage for RESET-		V_{RES}	-0.3	$V_{CC} + 0.3$	V
Power Dissipation ⁽¹⁾		P_d		0.625	W
Thermal Resistance, Junction to Ambient ⁽¹⁾		R_{thja}		200	$^{\circ}\text{C/W}$
Electrostatic Discharge Voltage	Human Body Model	V_{ESD}	1.5K		V
	Charge Device Model		500		
Junction Temperature		T_J		150	$^{\circ}\text{C}$
Storage Temperature		T_S	-55	150	$^{\circ}\text{C}$

Note:

- Thermal resistance and power dissipation ratings are measured per the following conditions:
 JESD51-2: Integrated Circuit Thermal Test Method Environment Conditions-Natural Condition (Still Air).
 JESD51-3: Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Package.

Note the following specific absolute maximum ratings, related to the analysis of the recharge path, for the FAN7085 from the datasheet:

- The absolute maximum power dissipation that can be tolerated by the product is shown as: $P_D = 625 \text{ mW}$.
- The absolute maximum junction temperature (not ambient temperature) that can be tolerated by the product is shown as: $T_J = 150^{\circ}\text{C}$.
- The device power dissipation rating is measured under the specific conditions shown in the table notes but every application results in a different rating depending on the specific thermal arrangement. The thermal resistance is shown as: $R_{thja} = 200^{\circ}\text{C/W}$.

Next, consider the maximum voltage drop across the recharge path (V_S , pin 5 and Gnd, pin 3) as stated in the data sheet³ and shown in Table 2. When the recharge path is activated (e.g., IN is HIGH and RESET is HIGH), with a maximum voltage of 1.2 V from V_S (pin 5) to Gnd (pin 3), there is a current of 1 mA as indicated in the data sheet.

Table 2. Statics Electrical Table (excerpt from FAN7085_GF085 datasheet; Recharge Path)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Recharge TE On-State Voltage Drop	V_{RECH}	$I_S = 1 \text{ mA}$, $V_{IN} = 5 \text{ V}$ at 125°C			1.2	V

² The reader is highly encouraged to obtain the latest version of the data sheet and work with those values.

³ TR means Ton Recharge, in other words, the recharge path is active.

Therefore, the maximum resistance under the conditions stated ($V_{CC}=5\text{ V}$; $V_{IN}=5\text{ V}$; $I_S=1\text{ mA}$; $T_A=125^\circ\text{C}$) is: $R_{DS(on)}125^\circ\text{C}=1.2\text{ V}/1.0\text{ mA} = 1.2\text{ k}\Omega$.

The range of resistance values, guaranteed by design over V_{CC} variations (5 V to 12 V), junction temperatures variations (T_J from -40°C to 150°C) and all manufacturing variations, are:

$$R_{DS(on)min} = 0.40\text{ k}\Omega$$

$$R_{DS(on)max} = 1.35\text{ k}\Omega$$

The power dissipated by the recharge path adds to any power dissipation by the output stage (current flowing into/out-of HO). The recharge instantaneous dissipation is calculated as $P_{TR} = V_{BS}^2/R_{DS(on)}$ (neglecting the small drop across the internal series diode). The following are examples of dissipation for two V_S to ground voltages (while IN is high and RESET is high):

For $V_{BS} = 48\text{ V}$

$$P_{TR(max)} = \frac{V_{BS}^2}{R_{ds(on)min}} = \frac{48^2}{0.40\text{ k}\Omega} = 5,760\text{ mW}; \quad P_{TR(min)} = \frac{V_{BS}^2}{R_{ds(on)max}} = \frac{48^2}{1.35\text{ k}\Omega} = 1,707\text{ mW};$$

For $V_{BS} = 28\text{ V}$

$$P_{TR(max)} = \frac{V_{BS}^2}{R_{ds(on)min}} = \frac{28^2}{0.40\text{ k}\Omega} = 1,960\text{ mW}; \quad P_{TR(min)} = \frac{V_{BS}^2}{R_{ds(on)max}} = \frac{28^2}{1.35\text{ k}\Omega} = 581\text{ mW};$$

The selected examples show that 3 of the 4 power dissipation's exceed the absolute maximum dissipation for the entire device. The only value that is less than the maximum ($P_{TR(min)}$ with V_{BS} at 28 V) leaves only 44 mW for driving the attached gate. More importantly, the only way to insure the highest $R_{DS(on)}$ value is used for an application, would be to measure each and every device (select only the highest) and/or limit the T_J temperature extremes.

Even if low duty cycle PWM techniques are employed, the power dissipation exceeds the absolute maximums (in some of the previous examples by a factor of over 9 times the 625 mW shown in the datasheet) and the total dissipation would be worse when the output stage dissipation is added.

If the solution is to limit T_J , the R_{thja} for the actual design must be considered. This means the ambient temperature will have to somehow be limited to a much lower value than 150°C . Take an example, when the recharge path is active with a V_S to Gnd voltage of 10 V, the worst case available dissipation for the HO drive is:

For $V_S = 10\text{ V}$

$$P_{TR(max)} = \frac{V_S^2}{R_{ds(on)min}} = \frac{10^2}{0.40\text{ k}\Omega} = 250\text{ mW}; \quad P_{HO(max)} = 625\text{ mW} - 250\text{ mW} = 375\text{ mW}$$

The first result (250 mW) is the power dissipated just for the TR active path. The second result (375 mW) is the power dissipation available for driving the load on the HO pin. The corresponding rise in temperature above ambient (using the thermal resistance as shown) is calculated s⁴:

$$\Delta T = P_{diss} \times \theta_{ja} = 375\text{ mW} \times 200 \frac{^\circ\text{C}}{\text{W}} = 75^\circ\text{C} \quad \text{Vs.} \quad 625\text{ mW} \times 200 \frac{^\circ\text{C}}{\text{W}} = 125^\circ\text{C}$$

So the TR active path alone raises the junction temperature 75°C above ambient and the combination of both, raises it 125°C above ambient.

Summary

The total power dissipation for any given application has to be calculated as the sum of the output stage power and the recharge path power. Neither the total power nor the individual power values must ever exceed the datasheet limit for maximum power dissipation because absolute maximum ratings indicate sustained limits beyond which damage to the device may occur.

When, for a given application, the power exceeds the limits of the FAN7085, another high-side gate driver product needs to be selected (one without an internal recharge path). Then, an external circuit needs to be developed, specific to the application that recharges the boot capacitor as needed.

⁴ More details on thermal analysis can be found in reference #

The author is Lawrence Durfee, applications Engineer in the Fairchild Automotive Group.

References

The following is a list of materials used to create this memo.

- [1] “FAN7085_GF085 – High Side Gate Driver with Recharge FET”, data sheet Rev 1.0.1 September 2012; Fairchild Semiconductor Corporation
http://www.fairchildsemi.com/ds/FA/FAN7085_GF085.pdf
- [2] “Design Guide for Selection of Bootstrap Components”, application note AN-9052 Rev 1.0.0 November 2008; Fairchild Semiconductor Corporation
<http://www.fairchildsemi.com/an/AN/AN-9052.pdf>
- [3] “Design and Application Guide of Bootstrap Circuit for High-Voltage Gate-Drive IC”, application note AN-6076 Rev 1.0.0 September 2008; Fairchild Semiconductor Corporation
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- [4] “Recommendations to Avoid Short Pulse Width Issues in HVIC Gate Driver Applications”, application note AN-8102 Rev 1.0.1 April 2014; Fairchild Semiconductor Corporation
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- [5] “Maximum Power Enhancement Techniques for SO-8 Power MOSFETs” application note AN -1029 Rev B Aug1998; Alan Li, Brij Mohan, Steve Sapp, Izak Bencuya, Linh Hong; ; Fairchild Semiconductor Corporation
<http://www.fairchildsemi.com/an/AN/AN-1029.pdf>

Related Datasheets

[FAN7085_GF085 — High Side Gate Driver with Recharge FETS](#)

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